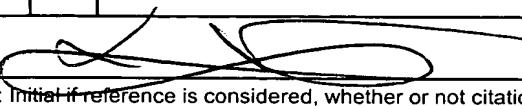
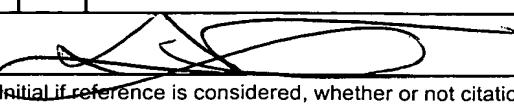


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 201326US2		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Minoru TAKAYA, et al.			
		FILING DATE HEREWITH		GROUP			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
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	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES      NO		
<i>✓</i>	AO	8-69712	03/12/96	Japan (with English Abstract)		X	
<i>✓</i>	AP	10-270255	10/09/98	Japan (with English Abstract)		X	
<i>✓</i>	AQ	11-192620	07/21/99	Japan (with English Abstract)		X	
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner 				Date Considered <i>11/02</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 201324US2		SERIAL NO. NEW APPLICATION	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Minoru TAKAYA, et al.			
		FILING DATE		Herewith		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO	
<i>2</i>	AO	10-270255	10/9/98	Japan (with English abstract)		X	
<i>2</i>	AP	6-14600	2/23/94	Japan (with English abstract)		X	
<i>2</i>	AQ	11-192620	7/21/99	Japan (with English abstract)		X	
<i>2</i>	AR	8-69712	3/12/96	Japan (with English abstract)		X	
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
	AX						
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	AZ						
Examiner 				Date Considered <i>11/02</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 201326US2	SERIAL NO. 09/749,800		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Minoru TAKAYA, et al.		RECEIVED OCT 3 1 2002 1775 1700			
		FILING DATE December 28, 2000		GROUP 1775			
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>SL</i>	AA	5,470,400	11/28/95	Y. BOGATIN, et al.			
	AB						
	AC						
	AD						
	AE						
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	AH						
	AI						
	AJ						
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	AL						
	AM						
	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO	
<i>SL</i>	AO	6-204021	07/22/94	JAPAN (with English Abstract)		X	
	AP	8-78798	03/22/96	JAPAN (with English Abstract)		X	
<i>SL</i>	AQ	0 383 035	08/22/90	EUROPE			
	AR	0 878 984	11/18/98	EUROPE			
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
<i>SL</i>	AW	G. VIAU, et al., Journal of Applied Physics, vol. 76, no. 10, Part 2, XP-000508787, pages 6570-6572, "PREPARATION AND MICROWAVE CHARACTERIZATION OF SPHERICAL AND MONODISPERSE Co <sub>20</sub> Ni <sub>80</sub> PARTICLES", November 15, 1994					
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>SL</i>						Date Considered 11/02	

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.